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United States Patent [19]

Wensley et al.

[11] **Patent Number: Des. 419,082**

[45] **Date of Patent: ** Jan. 18, 2000**

[54] **REFRACTOMETRIC ANALYZER**

[75] Inventors: **Martin Wensley**, Alameda; **Jeffrey Dickert**, Pleasanton, both of Calif.

[73] Assignee: **Techniquip**, Livermore, Calif.

[**] Term: **14 Years**

[21] Appl. No.: **29/099,428**

[22] Filed: **Jan. 21, 1999**

[51] **LOC (7) Cl.** **10-04**

[52] **U.S. Cl.** **D10/78**

[58] **Field of Search** D10/78; 356/445, 356/135, 136, 133; 250/573

[56] **References Cited**

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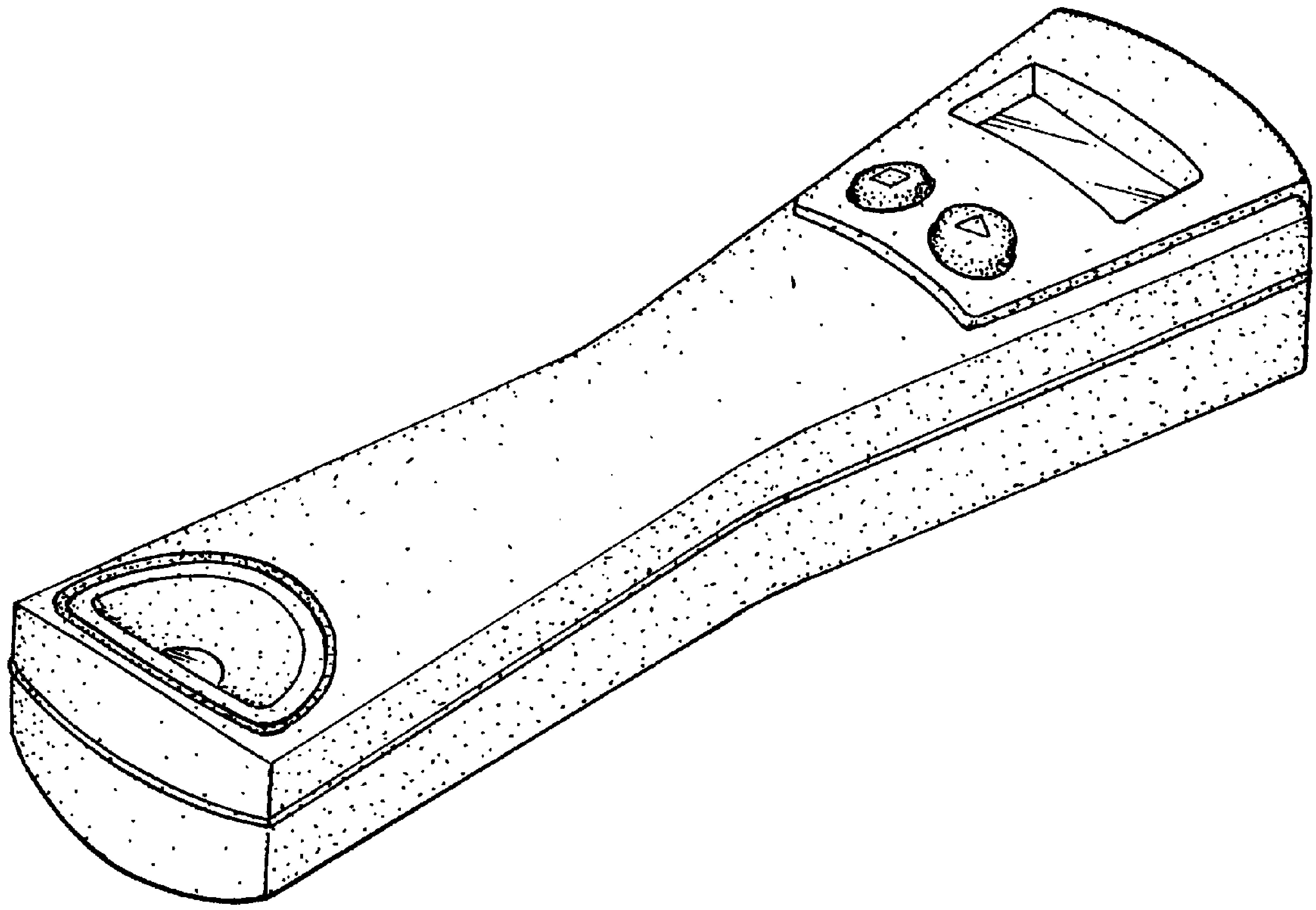
[57] **CLAIM**

The ornamental design for refractometric analyzer, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a refractometric analyzer showing my new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a top plan view thereof;
FIG. **4** is a rear elevational view thereof;
FIG. **5** is a right side elevational view thereof;
FIG. **6** is a bottom plan view thereof; and,
FIG. **7** is a left side elevational view thereof.

1 Claim, 2 Drawing Sheets



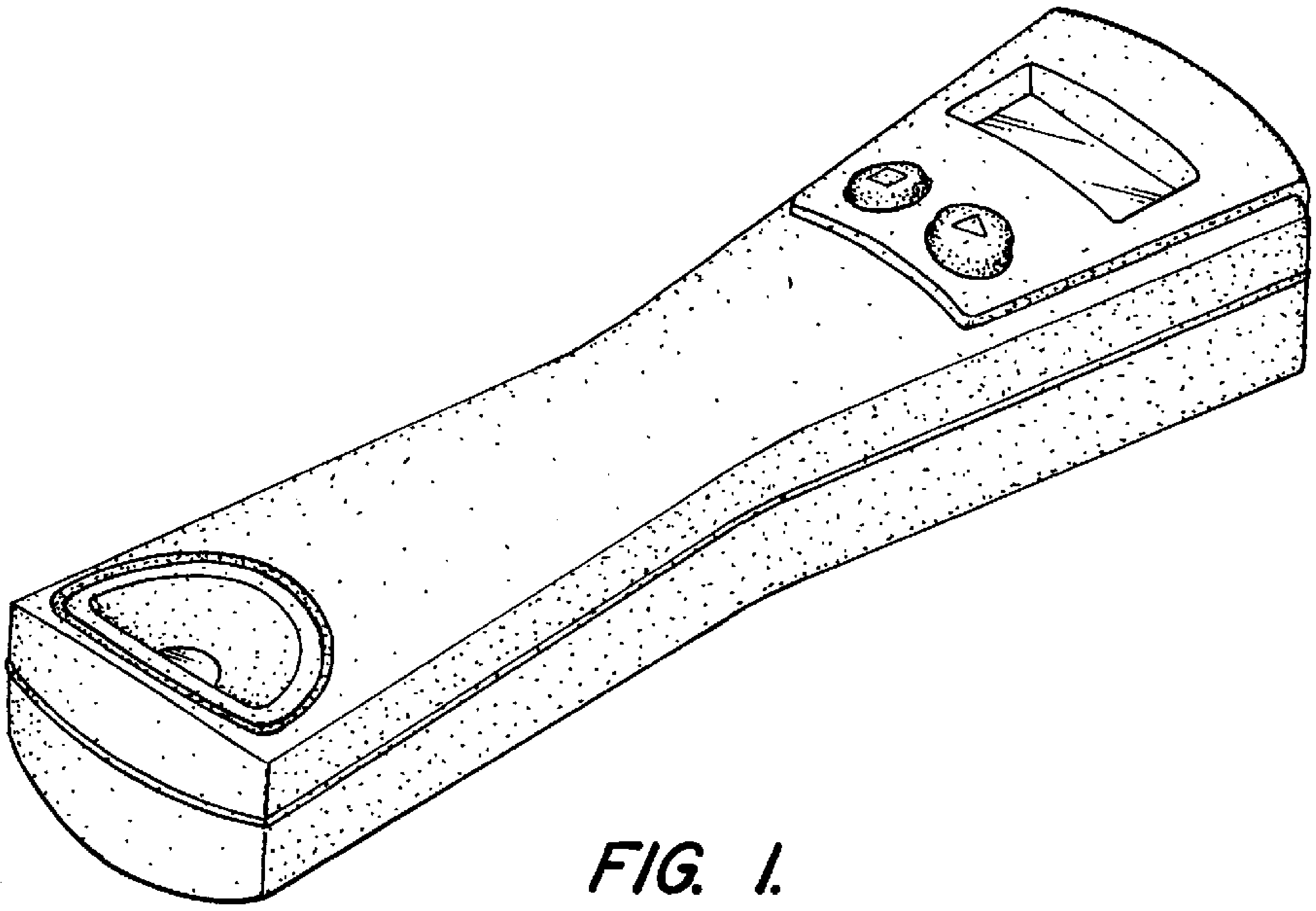


FIG. 1.

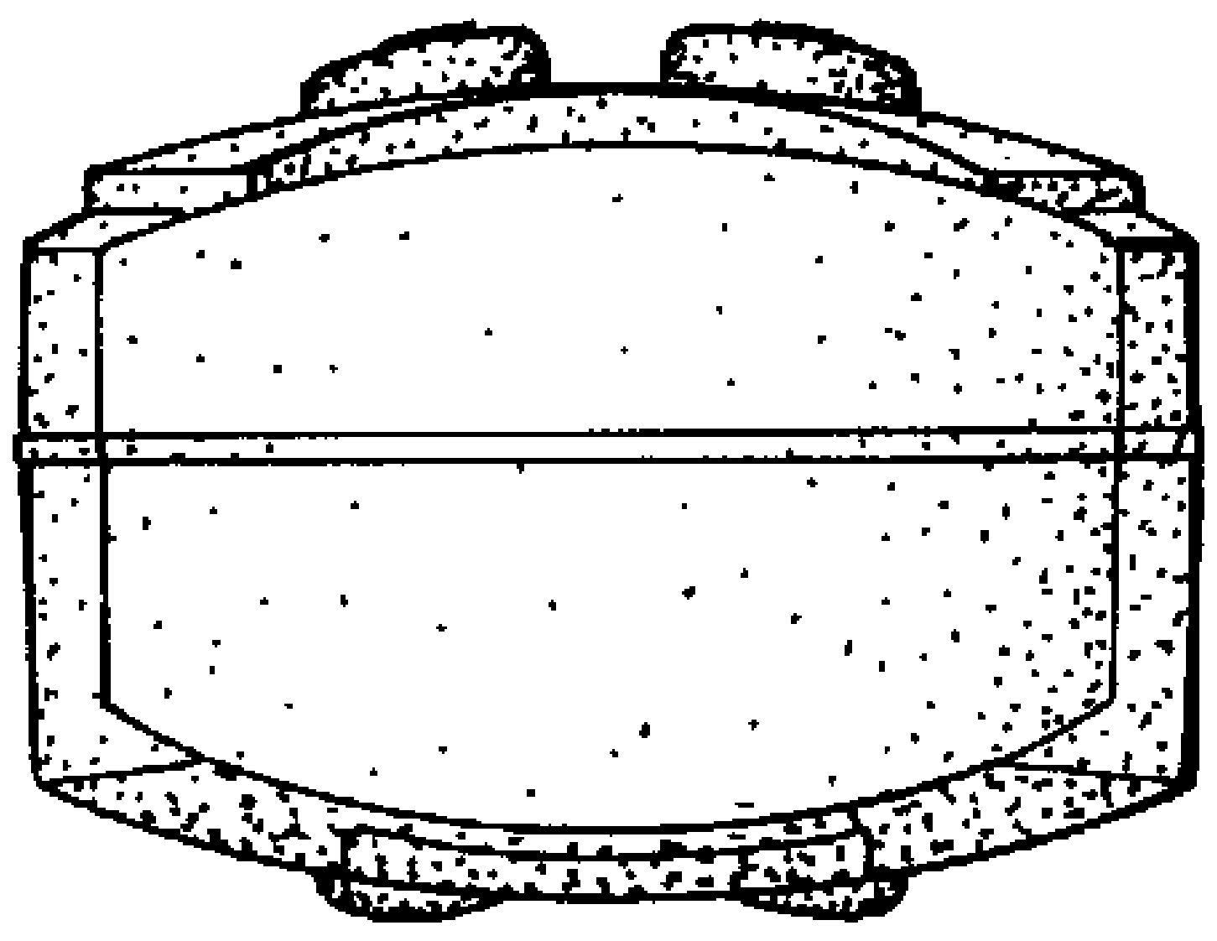


FIG. 2.

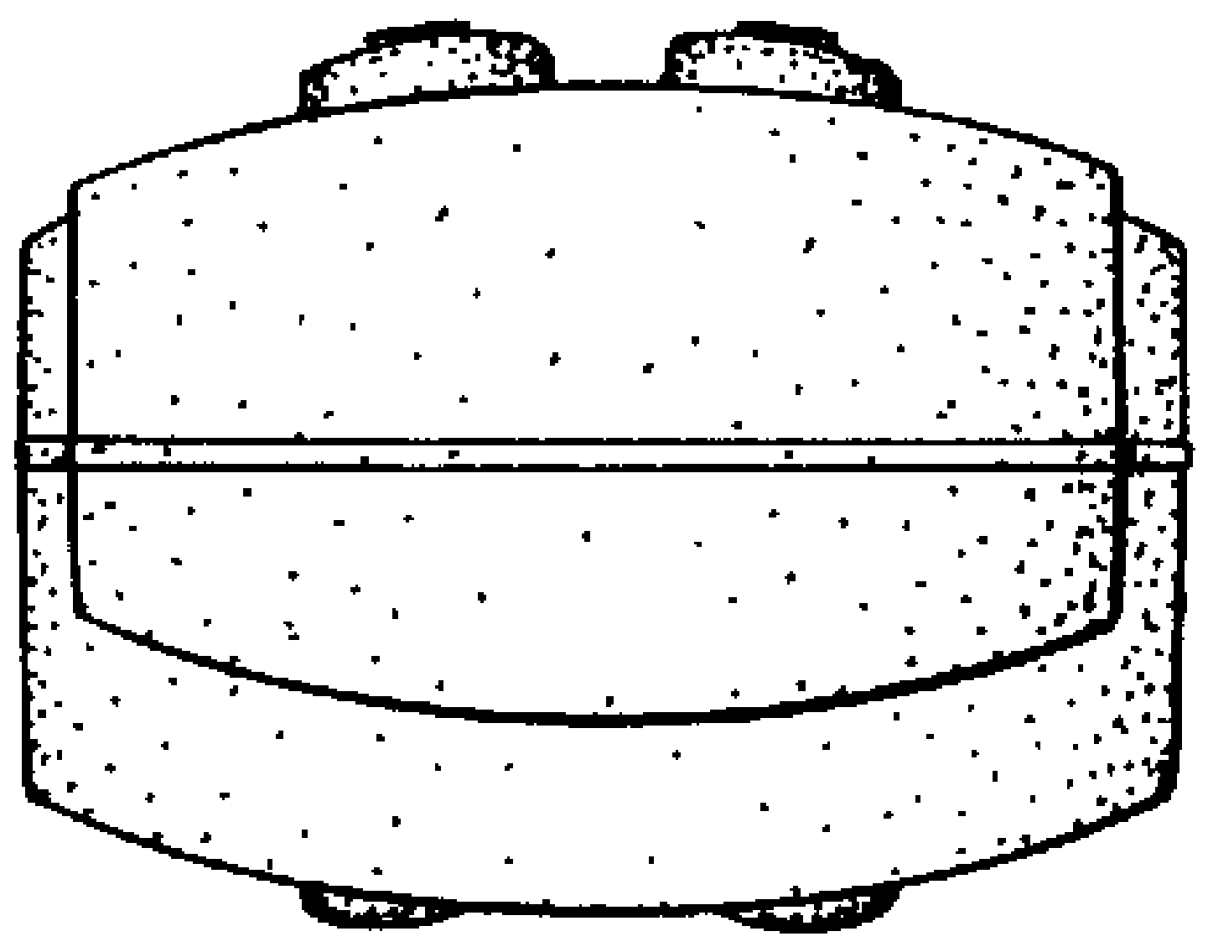


FIG. 4.

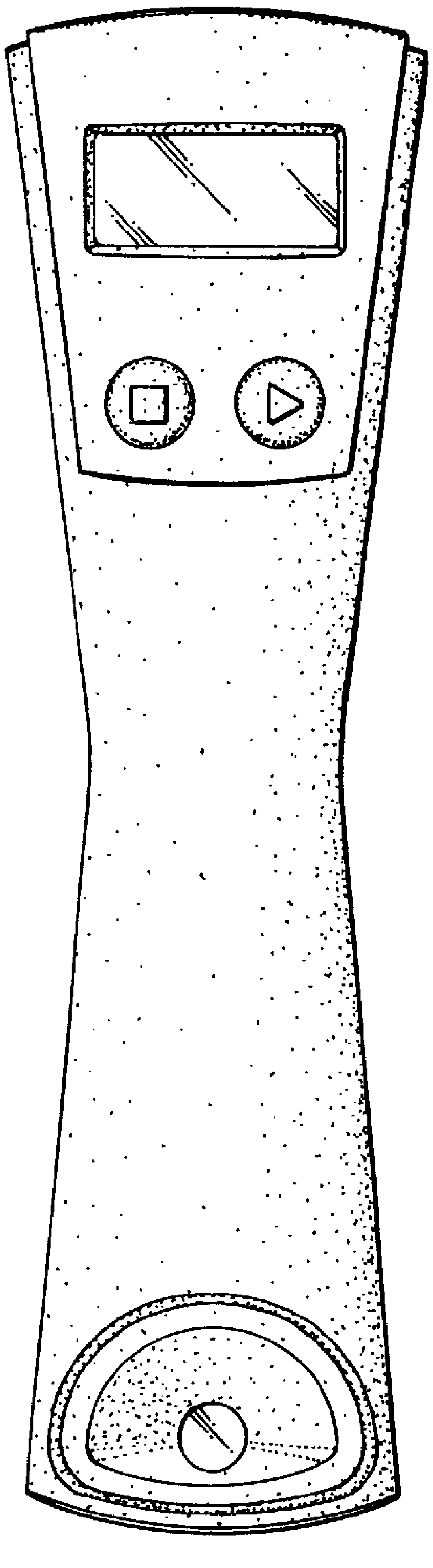


FIG. 3.

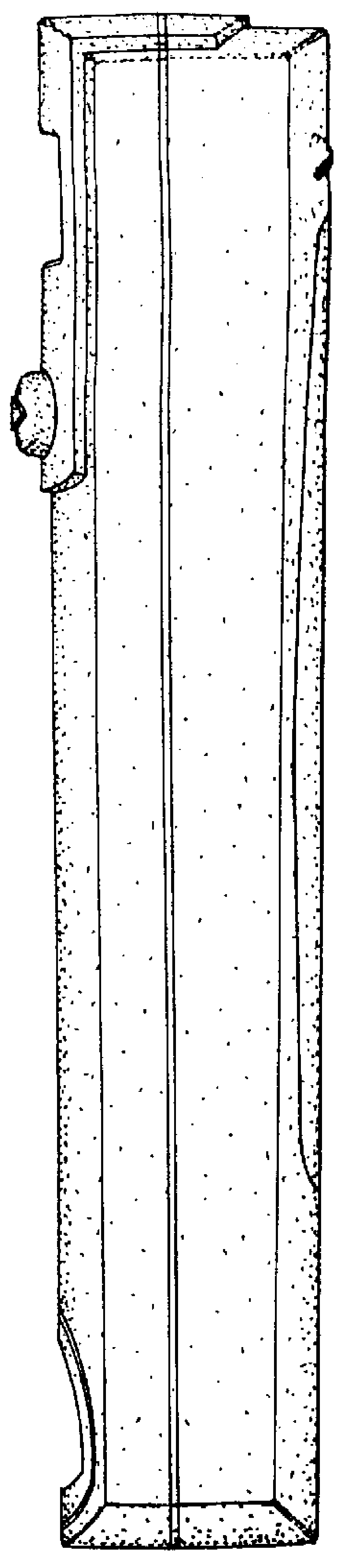


FIG. 5.

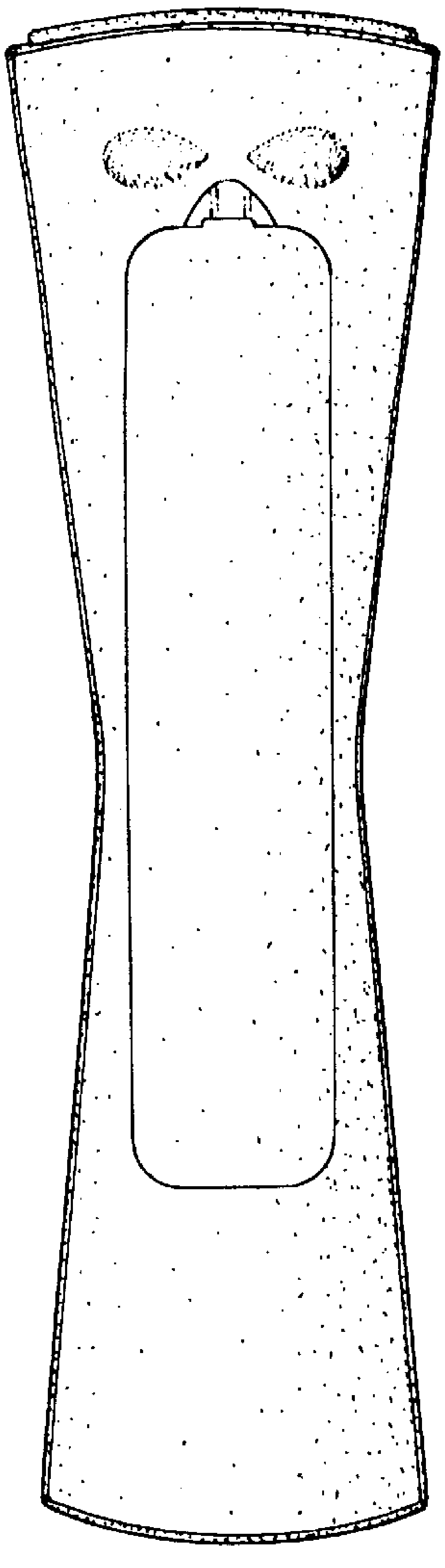


FIG. 6.

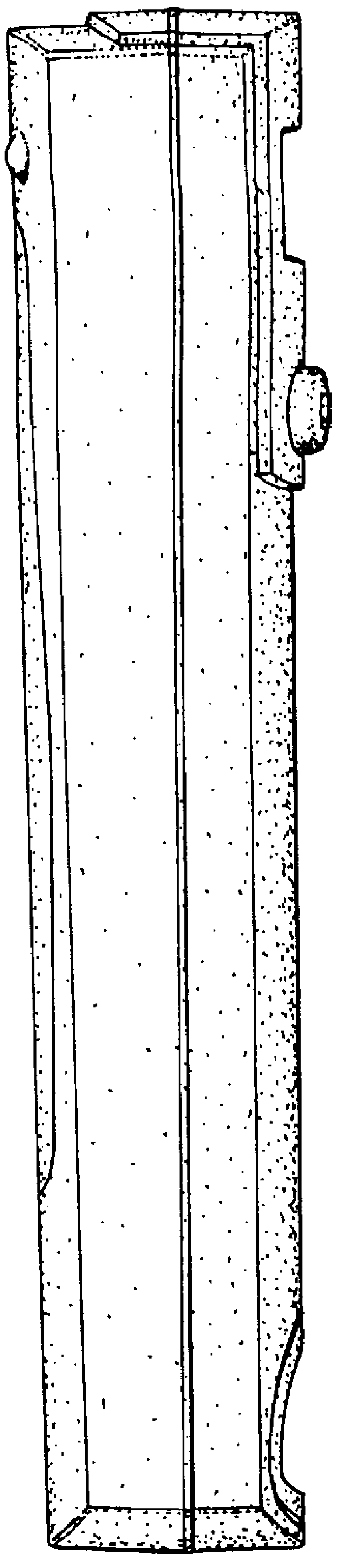


FIG. 7.